

Notice of References Cited

Application/Control No.

10/538,202

Applicant(s)/Patent Under
Reexamination
CHANG, CHIN

Examiner

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Art Unit

2624

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0076056	04-2003	Schuurmans, Frank Jeroen Pieter	315/291
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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